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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

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Sheet 1 of 1

Complete if Known

Application Number	09/876,915
Filing Date	June 8, 2001
First Named Inventor	Wilhelm
Art Unit	2624
Examiner Name	Desire, G.
Attorney Docket Number	46872-254525

NON PATENT LITERATURE DOCUMENTS

Examiner Initials *	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	1	EDGEWORTH, R. et al., "Adaptive sampling for coordinate metrology," Precision Engineering, Vol. 23, pp. 144-154, 1999.	
	2	EDGEWORTH, R. et al., "Measurement uncertainty due to work-piece error interaction with sampling period," Center of Precision Metrology, Department of Mechanical Engineering and Engineering Science, The University of North Carolina at Charlotte, 1999.	
	3	ELKOTT, D. et al., "Isoparametric line sampling for the inspection planning of sculptured surfaces," Computer-Aided Design, Vol. 37, pp. 189-200, 2005.	
	4	ELKOTT, D. et al., "CAD-based sampling for CMM inspection of models with sculptured features," Engineering with Computers, Vol. 23, pp. 187-206, 2007.	
	5	ELKOTT, D. et al., "Automatic sampling for CMM inspection planning of free-form surfaces," International Journal of Production Research, Vol. 40, No. 11, pp. 2653-2676, 2002.	
	6	HUANG, J., "An efficient approach for solving the straightness and the flatness problems at large number of data points," Computer-Aided Design, Vol. 35, pp. 15-25, 2003.	
	7	PEDONE, P. et al., "Kriging-based sequential inspection plans for coordinate measuring machines," Applied Stochastic Models in Business and Industry, Vol. 25, pp. 133-149, 2009.	
	8	SAVIO, E. et al., "Metrology of freeform shaped parts," Annuals of the CIRP, Vol. 56, No. 2, pp. 810-835, 2007.	
	9	SUMMERHAYS, K. et al., "Optimizing discrete point sample patterns and measurement data analysis on internal cylindrical surfaces with systematic form deviations," Precision Engineering Journal of the International Societies for Precision Engineering and Nanotechnology, Vol. 26, pp. 105-121, 2002.	
	10	WILHELM, R. et al., "Task specific uncertainty in coordinate measurement," Center for Precision Metrology, Department of Mechanical Engineering and Engineering Science, University of North Carolina at Charlotte, USA.	

Examiner Signature		Date Considered	
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached.

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